

● PRINTER RUSH ●

(PTO ASSISTANCE)

Application : <u>09/916,215</u>	Examiner : <u>Peyton</u>	GAU : <u>2182</u>
From: <u>DP</u>	Location: <u>IDC</u> FMF FDC	Date: <u>1/10/06</u>
Tracking #: <u>epm 09/916,215</u> Week Date: <u>12/5/2005</u>		

DOC CODE	DOC DATE	MISCELLANEOUS
<input type="checkbox"/> 1449		<input type="checkbox"/> Continuing Data
<input type="checkbox"/> IDS		<input type="checkbox"/> Foreign Priority
<input type="checkbox"/> CLM		<input type="checkbox"/> Document Legibility
<input type="checkbox"/> IIFW		<input type="checkbox"/> Fees
<input type="checkbox"/> SRFW		<input type="checkbox"/> Other
<input type="checkbox"/> DRW		
<input type="checkbox"/> OATH		
<input type="checkbox"/> 312		
<input checked="" type="checkbox"/> SPEC	<u>7/25/2001</u>	

[RUSH] MESSAGE: Specification: page 15 Line # 28 Application Serial No. 09/ is missing, please resolve.

*There is nothing missing on page 15 line 28.

Page 12 there is a serial number missing
Ref (pubs) Thank you.

[XRUSH] RESPONSE: _____

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INITIALS: ky

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 REV 10/04

The charging time-constant of the resistor 502 and capacitor 503 combination is selected to prevent voltage 510 from reaching the trip level 511 of Comparator 506 during a "0" time period. When a "0" clock edge 540 of FIG. 6 occur, SPI Data-Out 515 to the Peripheral Device 600 a "0" can be clocked in. In a like manner, the time period for a "1" is long enough to ensure that the Comparator 504 trip level 511 is reached before the clock edge 540 FIG. 7 occurs and a "1" is clocked in.

In order to hold the most recent "bit" value for use by Asynchronous type Peripheral Devices, the Comparator 504 output 517 is applied as input to NAND gate 507 and its inverted state, via Inverter 521, is applied to the input of NAND gate 519. While the Data-Out + Clock signal 301 is low, the pull-down resistor 508 holds the second input of NAND gates 519 and 507 low keeping their respective outputs 533 and 531 high. As the Data-Out + Clock signal 301 (or 401) goes high at the end of a bit period, voltage 516 is also pulled high for a period, controlled by the time constant of resistor 508 and capacitor 506, briefly enabling NAND gates 519 and 507, thus enabling the flip-flop made up of NAND gates 523 and 524 to latch the state of 517 as follows: (A) if voltage 517 is high, the output of NAND gate 507 becomes low thus setting the flip-flop made up of NAND gates 523 and 524 such that output 525 latches high representing a "1" Data-Out 525 for UART; and (B) in a similar manner, if signal 517 is low, the output of NAND gate 519 becomes low causing the flip-flop output 525 latches low, representing a "0" for UART Data-Out 525.

Isolation circuitry 400 for electrically isolating high voltage inputs and outputs from the low voltage logic levels signals of the host may optionally but advantageously be provided between Data Direction Multiplexer 300 and Data-Out extractor 500. An embodiment of isolation circuitry 400 is show in FIG. 9 and described in greater detail hereinbelow and in co-pending United States Patent Application Serial No. 09/9/5,188 filed 25 July 2001 (Attorney Docket No. A-70826/RMA) entitled *System, Device, And Method For Comprehensive Input/Output Interface Between Process Or Machine Transducers And Controlling Device Or System*. In the illustrated embodiment, Data-Out+Clock 311 passes